

PATENT  
5589-05001/P1032

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:  
Xu et al.

Serial No. 10/699,352

Filed: October 31, 2003

For: METHODS AND SYSTEMS FOR  
DETERMINING AN ELECTRICAL  
PROPERTY OF AN INSULATING  
FILM

Group Art Unit: 2858  
Examiner: Unknown

Atty. Dkt. No. 5589-05001

I hereby certify that this correspondence is being deposited  
with the U.S. Postal Service as First Class Mail in an envelope  
addressed to: Commissioner for Patents, P.O. Box 1450,  
Alexandria, VA 22313, on the date indicated below:

5/5/04  
Date

Pamela Gerik  
Pamela Gerik

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313

Sir/Madam:

Applicant requests consideration of ☒ the references listed on the attached Form PTO-1449  
and/or ☐ the additional information identified below in paragraph 3. A copy of each reference listed on  
the Form PTO-1449 is enclosed.

1. This Information Disclosure Statement is submitted:

- a. ☐ within 3 months of the filing date of a national application other than a continued prosecution application under § 1.53(d);  
☐ within 3 months of the date of entry of the national stage as set forth in § 1.491 in an International application;  
☒ before the mailing date of a first Office Action on the merits; or  
☐ before the mailing of a first Office Action after the filing of a request for continued examination under § 1.114.
- b. ☐ after the events of above paragraph 1a and prior to the mailing date of a final Office Action or Notice of Allowance, and thus: ☐ the certification of paragraph 2 below is provided, or ☐ a fee of \$180.00 is enclosed.
- c. ☐ after the mailing date of a final Office Action or a Notice of Allowance and prior to payment of the issue fee, and thus: the certification of paragraph 2 below is provided and a fee of \$180.00 is enclosed.

2. It is hereby certified:

- ☐ that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or
- ☐ that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in § 1.56 (c) more than three months prior to the filing of the Statement.

3. ☐ Consideration of the following additional information (including any co-pending or abandoned U.S. applications, prior uses and/or sales, etc.) is requested:

4. For each non-English language reference listed on the attached Form PTO-1449:

- ☐ reference is made to an English language translation submitted herewith, and/or
- ☐ reference is made to a foreign patent office search report (in the English language) submitted herewith, and/or
- ☐ reference is made to an English language translation of a foreign patent office search report submitted herewith, and/or
- ☐ reference is made to the concise explanation contained in the specification of the present application at page(s) \_\_\_\_\_, and/or
- ☐ reference is made to the concise explanation set forth below:

5. ☐ Applicant also offers the following comments for the Examiner's consideration:

6. ☐ Also enclosed is a copy of a foreign search report citing these references.

7. ☐ The listed documents were brought to the attention of the Applicant(s) after payment of the issue fee in the captioned case. The documents were cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. Applicant(s) request this Information Disclosure Statement and attached Form PTO-1449 be placed in the file of the captioned application.

8. ☐ Applicant(s) requests that the Information Disclosure Statement and attached Form PTO-1449 and references, which are being filed before the grant of the patent and pursuant to 37 C.F.R. § 1.97(i), be placed in the file of the captioned application.

If any required fees are missing, the Commissioner is authorized to charge said fees to Conley Rose, P.C. Deposit Account No. 03-2769/5589-05001.

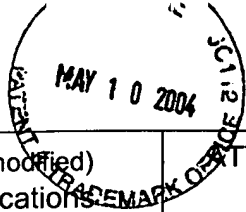
Respectfully submitted,



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Date: 5-5-04



**Form PTO-1449** (modified)  
List of Patents and Publications  
For Applicant's Information  
Disclosure Statement  
(Use several sheets if necessary)

PATENT. DKT. NO. 5589-05001

APPLICANT: Xu et al.

FILING DATE: October 31, 2003

SERIAL NO. 10/699,352

GROUP: 2858

**U.S. PATENT DOCUMENTS**

| EXAM.<br>INITIALS | REF.<br>DES. | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB<br>CLASS | FILING DATE IF<br>APPROPRIATE |
|-------------------|--------------|-----------------|------|------|-------|--------------|-------------------------------|
|                   |              |                 |      |      |       |              |                               |
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|                   |              |                 |      |      |       |              |                               |

**FOREIGN PATENT DOCUMENTS**

| EXAM.<br>INITIALS | REF.<br>DES. | DOCUMENT NUMBER | DATE       | COUNTRY | CLASS | SUB<br>CLASS | TRANSLATION<br>YES/NO |
|-------------------|--------------|-----------------|------------|---------|-------|--------------|-----------------------|
|                   | A1           | 98/57358        | 1998-12-17 | WO      |       |              |                       |
|                   |              |                 |            |         |       |              |                       |
|                   |              |                 |            |         |       |              |                       |

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

|  |    |   |
|--|----|---|
|  | A2 | Cosway et al., "Manufacturing Implementation of Corona Oxide Silicon (COS) Systems for Diffusion Furnace Contamination Monitoring," 1997 IEEE/SEMI Advanced Semiconductor Manufacturing Conference, pp. 98-102. |
|  | A3 | Miller, "A New Approach for Measuring Oxide Thickness," Semiconductor International, July 1995, pp. 147-148.  |
|  | A4 | <u>Numerical Recipes in C, The Art of Scientific Computing, 2nd Ed.</u> , © Cambridge University Press 1988, 1992, p. 683.  |
|  | A5 | Weinberg, "Tunneling of Electrons from Si into Thermally Grown SiO <sub>2</sub> ," Solid-State Electronics, 1977, Vol. 20, pp. 11-18.   |
|  | A6 | Verkuil, "Rapid Contactless Method for Measuring Fixed Oxide Charge Associated with Silicon Processing," IBM Technical Disclosure Bulletin, Vol. 24, No. 6, 1981, pp. 3048-3053.                                |
|  | A7 | "Contactless Photovoltage vs. Bias Method for Determining Flat-Band Voltage," IBM Technical Disclosure Bulletin, Vol. 32, Vol. 9A, 1990, pp. 14-17.   |
|  | A8 | "Contactless Electrical Equivalent Oxide Thickness Measurement," IBM Technical Disclosure Bulletin, Vol. 29, No. 10, 1987, pp. 4622-4623.   |
|  |    |   |

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.